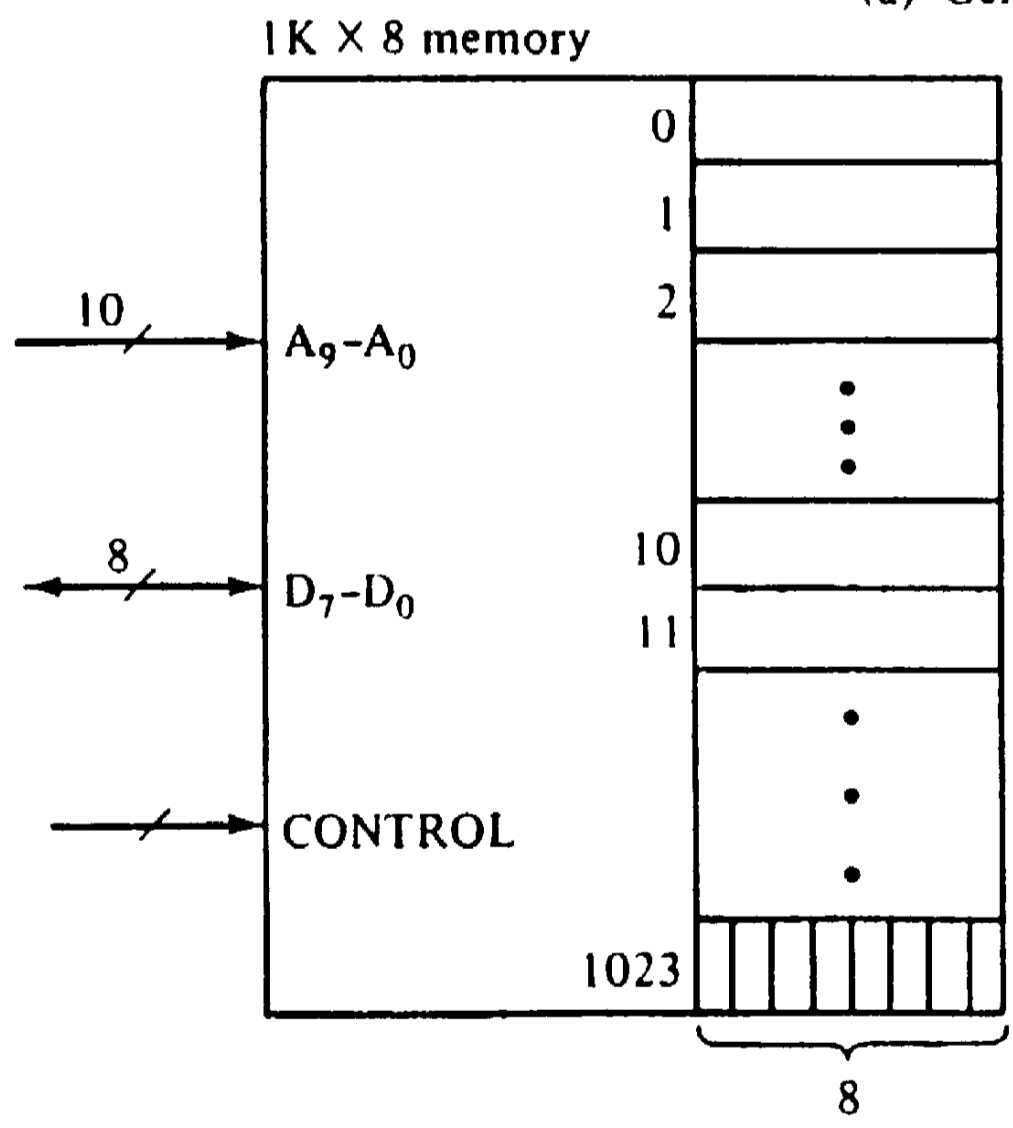
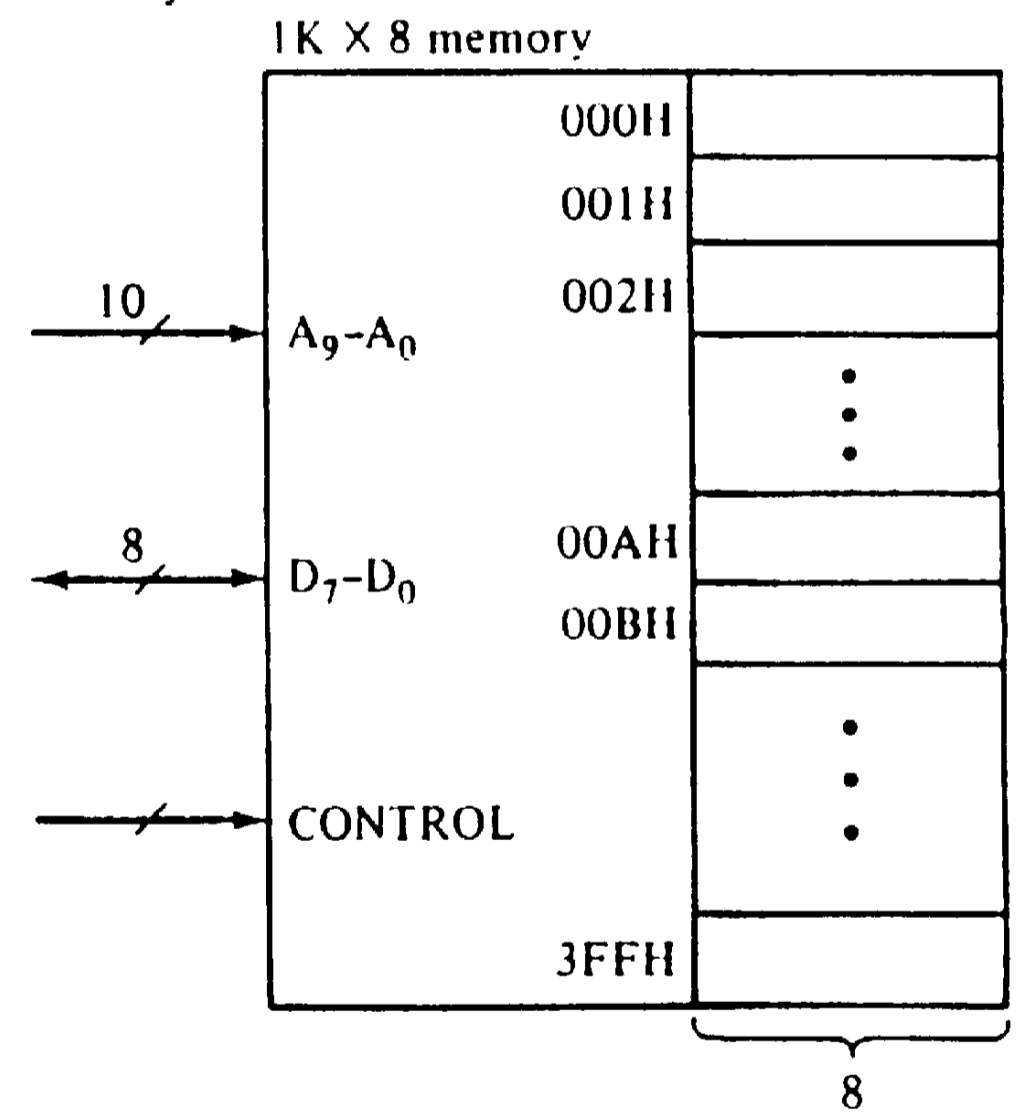


(a) General model of a memory

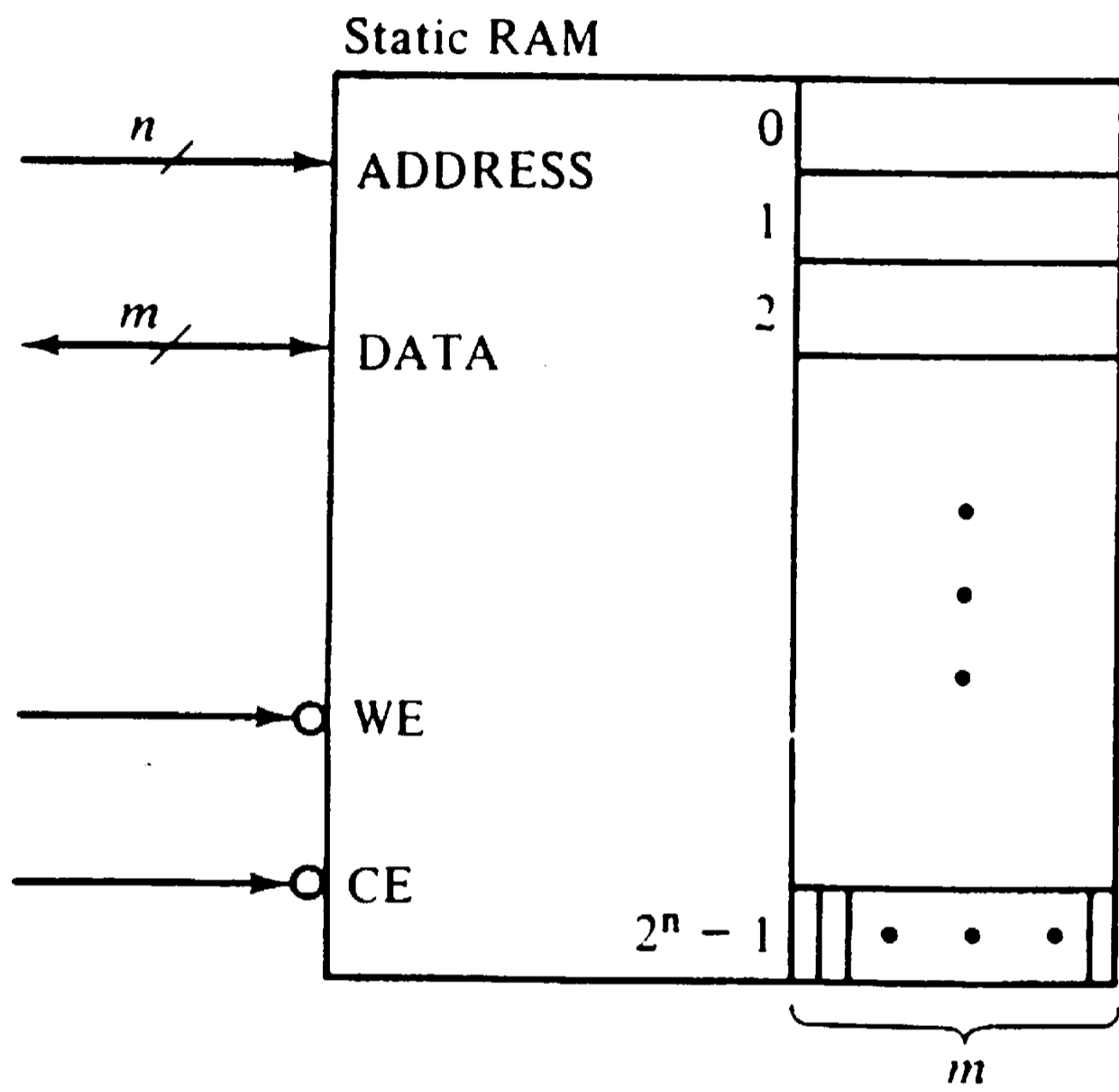


(b) 1K x 8 memory with addresses in decimal



(c) 1K x 8 memory with addresses in hexadecimal

Figure 6.21 Models of memories.



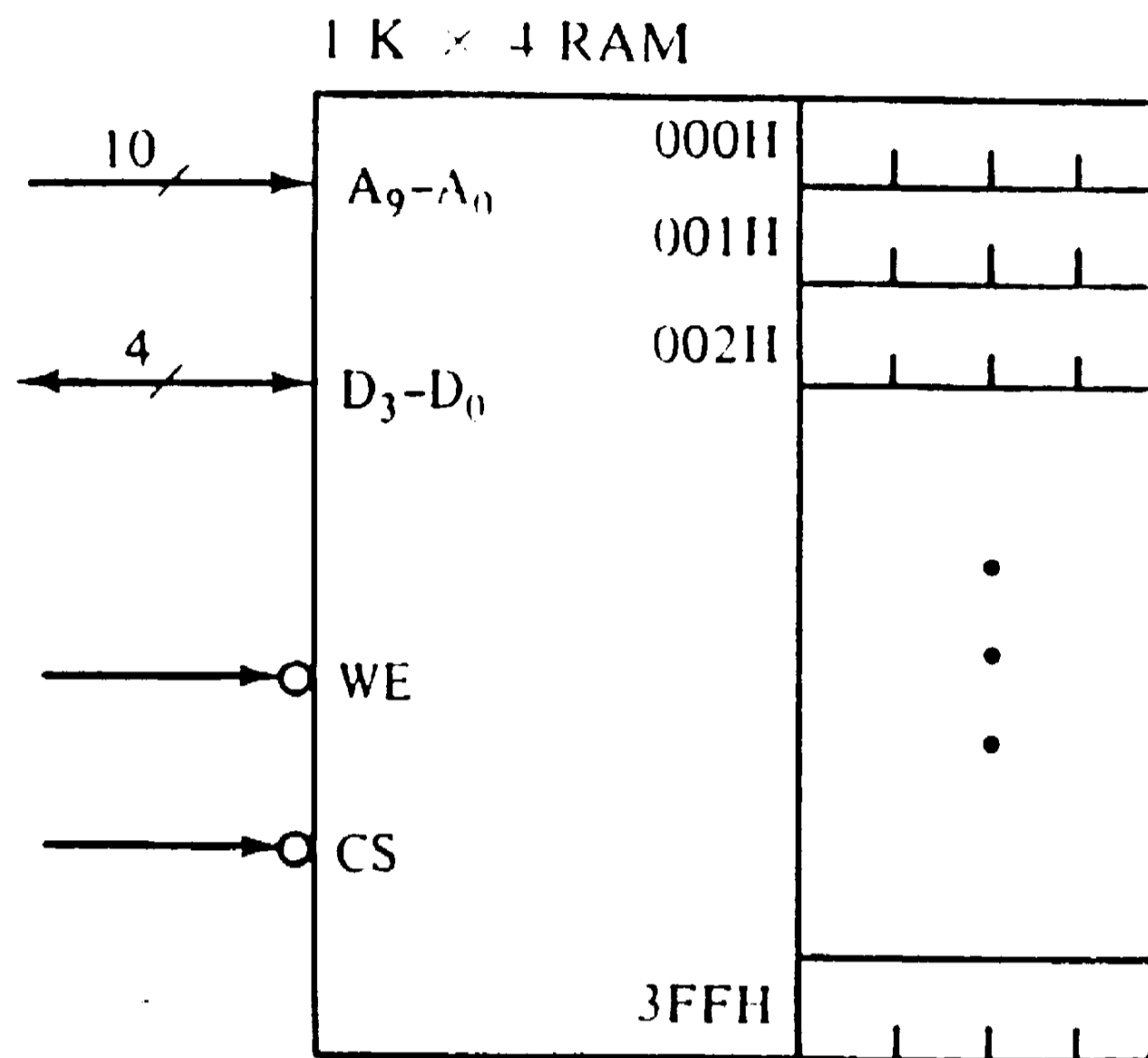
(a) A model of static RAM

Operation	CE	WE
Disable RAM	F(H)	X
Read	T(L)	F(H)
Write	T(L)	T(L)

Where F: false
 T: true
 X: don't care
 L: low
 H: high

(b) Operations

Figure 6.22 Static RAM.



(a) Block diagram

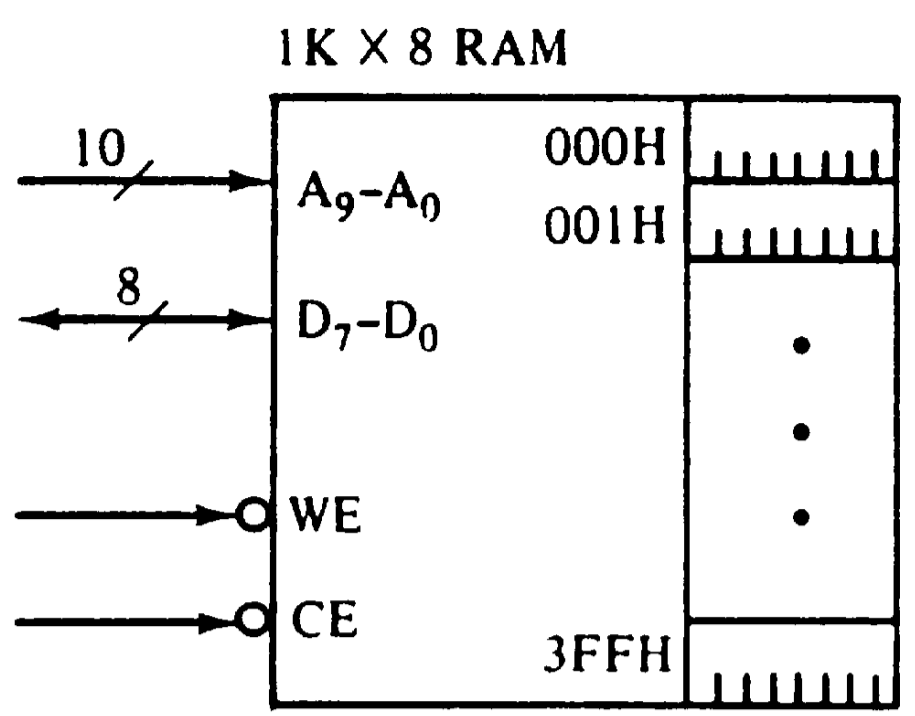
Operation	CS	WE
High-Z outputs	H	X
Read	L	H
Write	L	L

Where L: Low-voltage level
H: High-voltage level
X: Don't care

(b) Operations and control

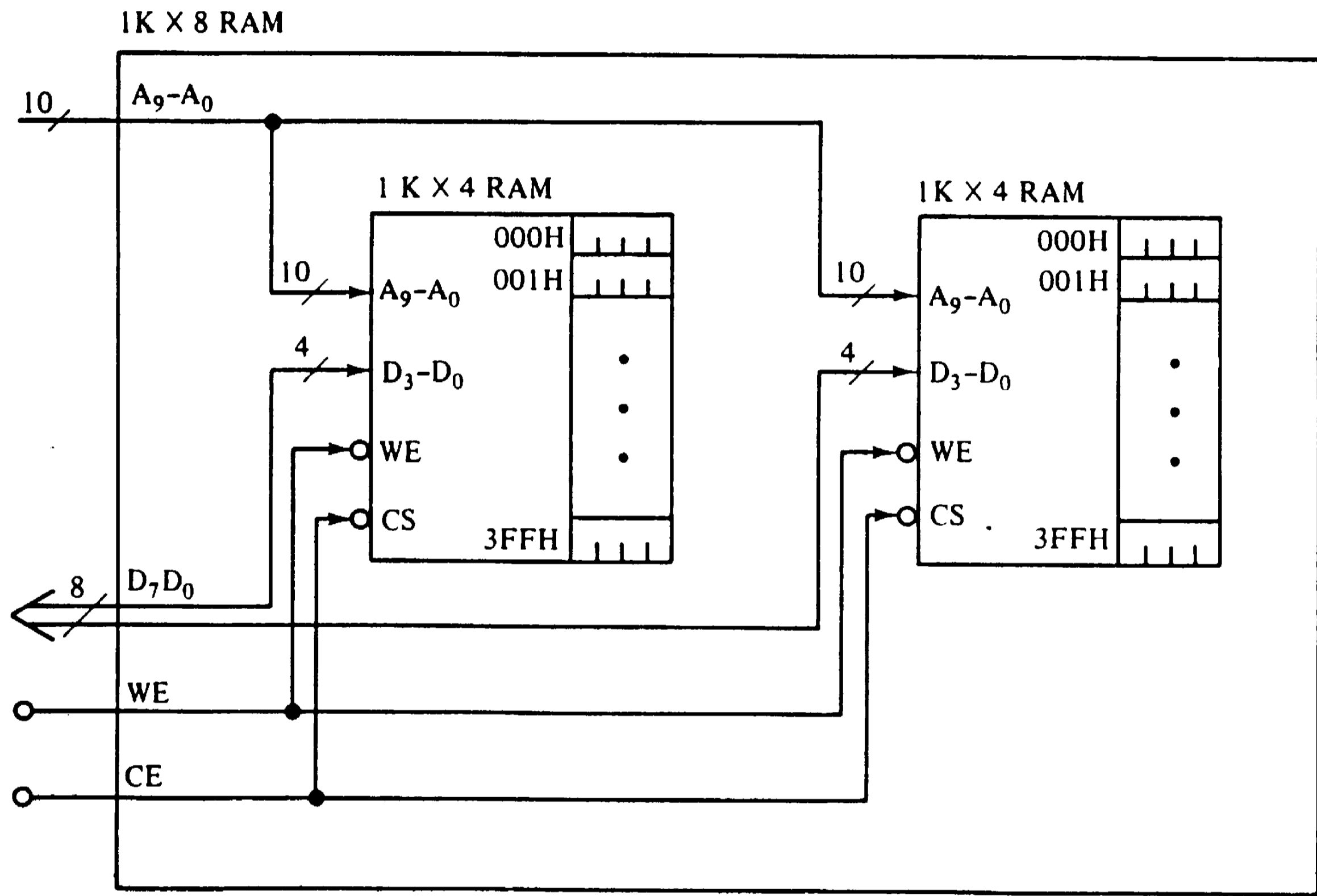
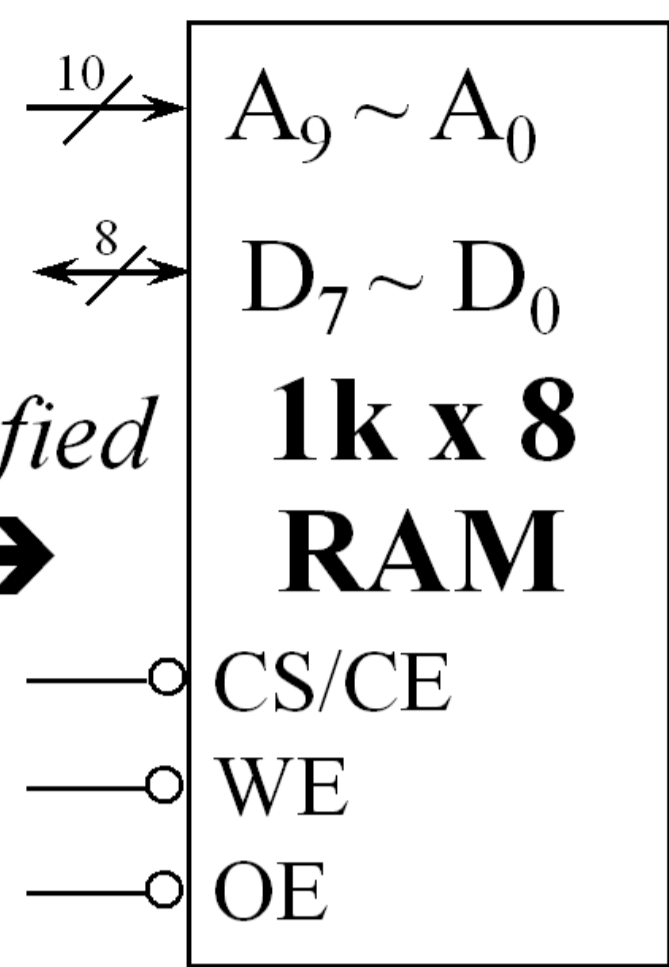
Figure 6.23 Typical commercially available 1K × 4 RAM.

- Sometimes block diagrams for SRAM are simplified, removing OE(L).
 - > Since WE(L) has higher priority than OE(L), OE(L) can be always true, i.e., GND.
 - > In this case, if WE is true, writing to SRAM; otherwise reading.



(a) Block diagram of a 1K x 8 RAM

Un-simplified SRAM →



(b) Realization with two 1K x 4 RAMs

Figure 6.24 Realization of a 1K x 8 RAM.

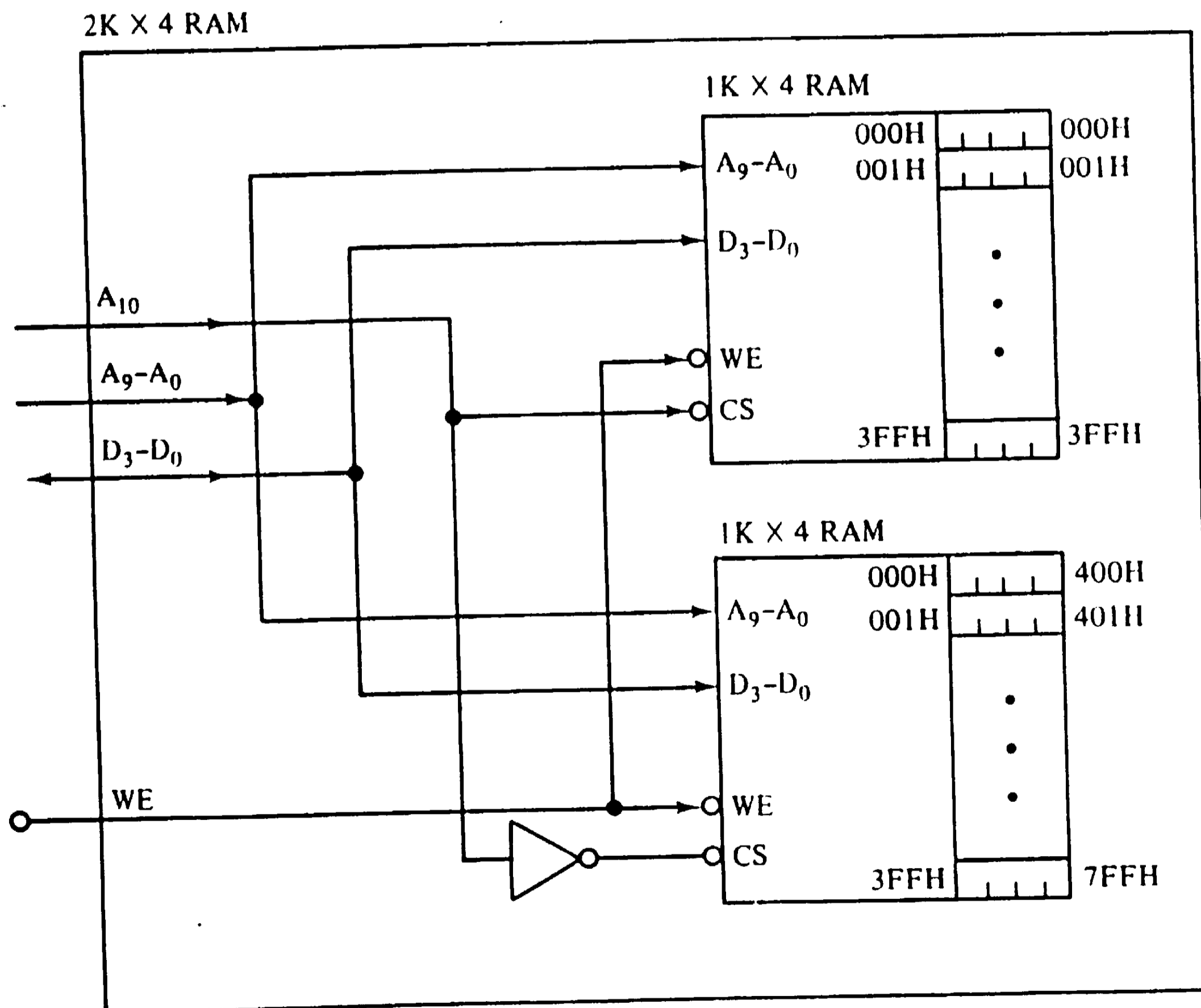
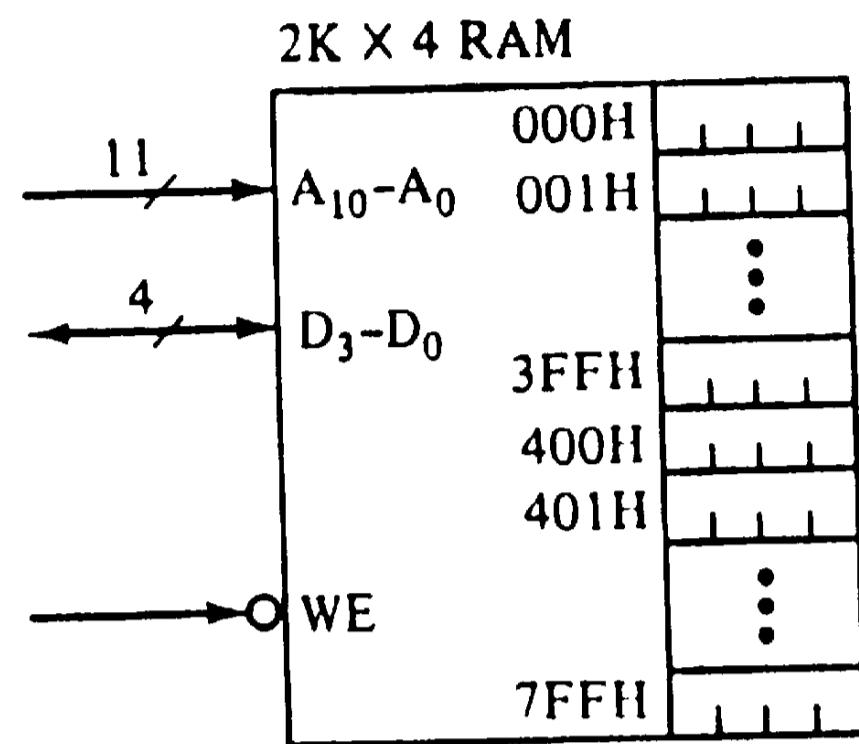


Figure 6.25 Realization of a 2K × 4 RAM.

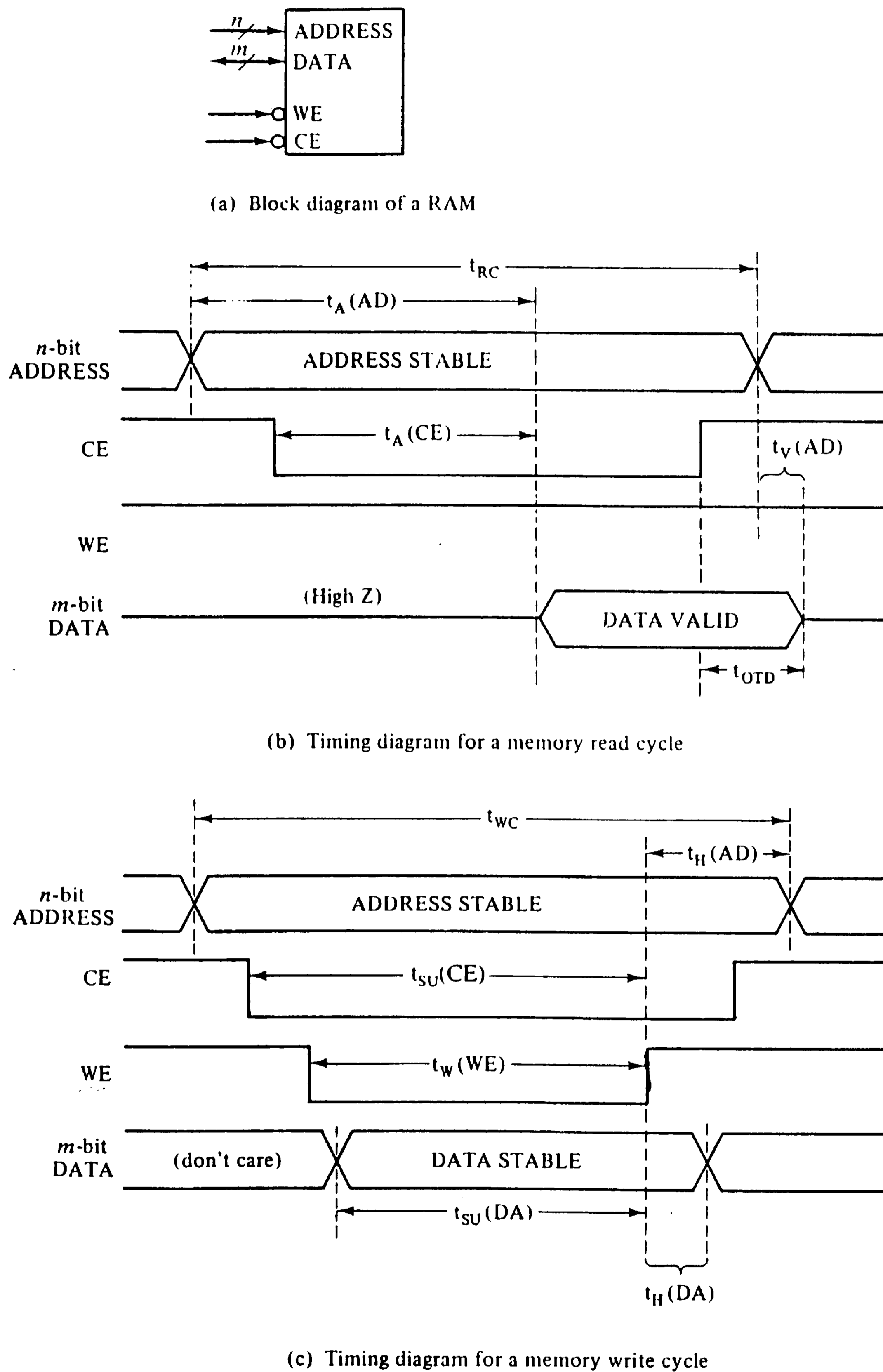
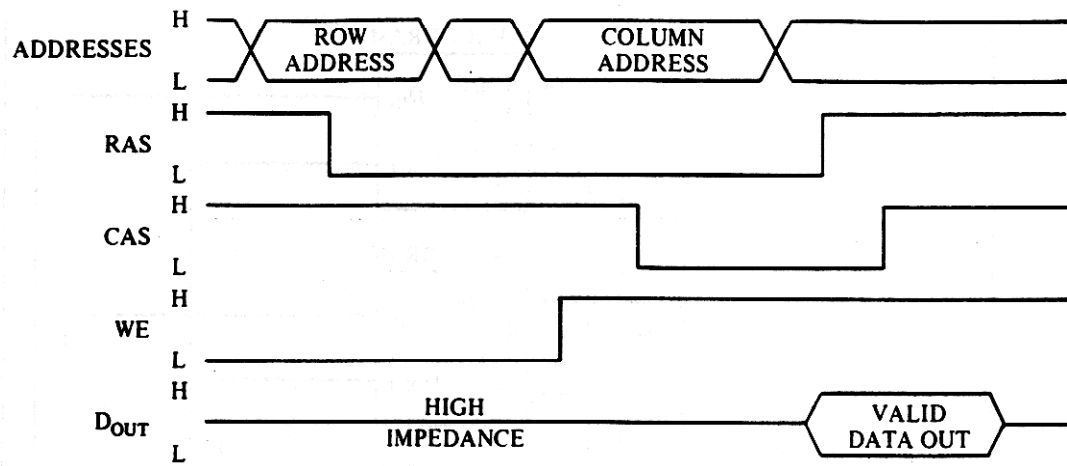
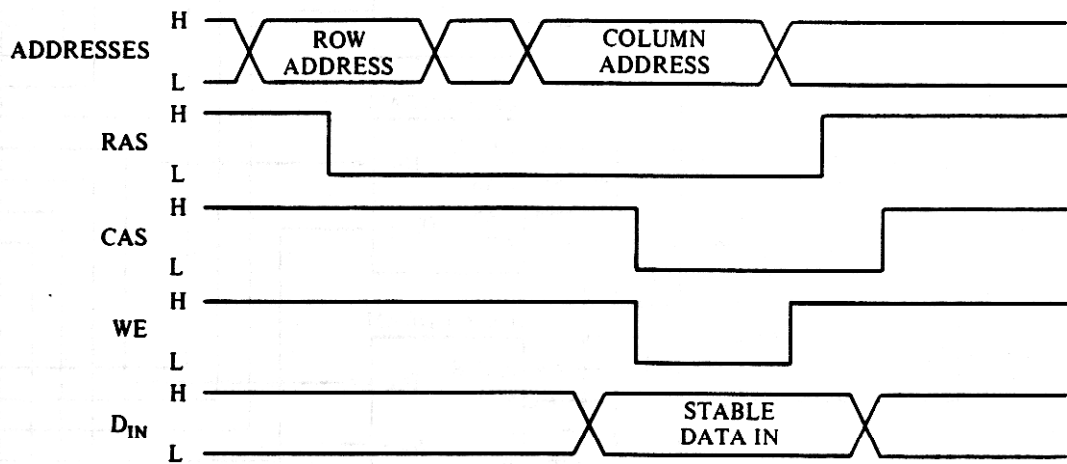


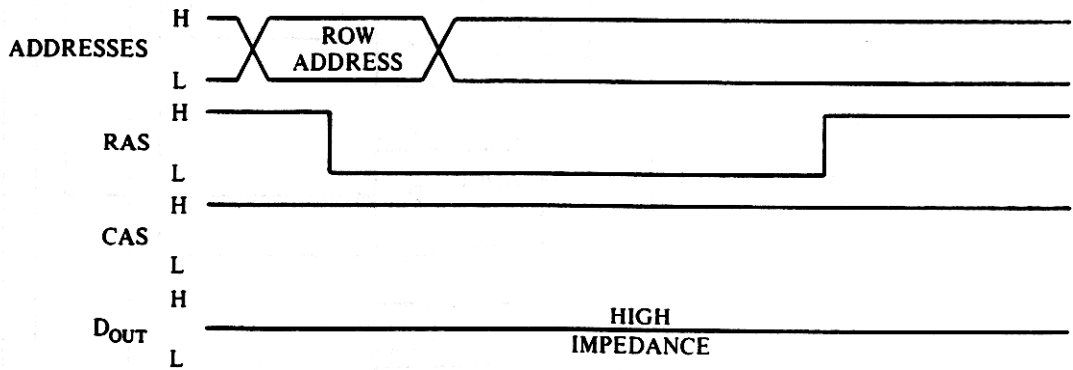
Figure 6.26 Memory read and memory write cycles.



(a) Read cycle

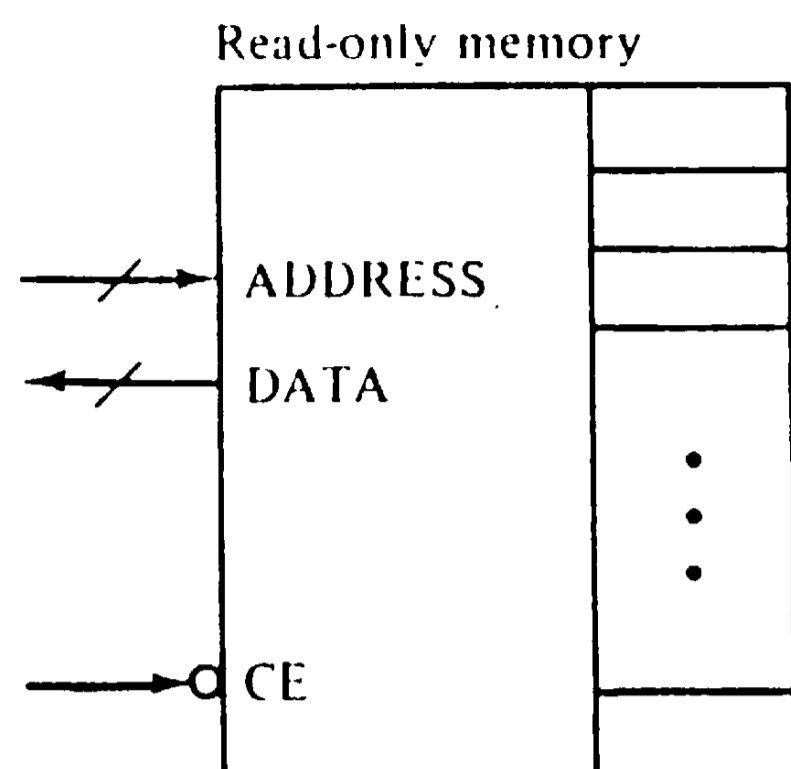


(b) Write cycle



(c) RAS-only refresh cycle

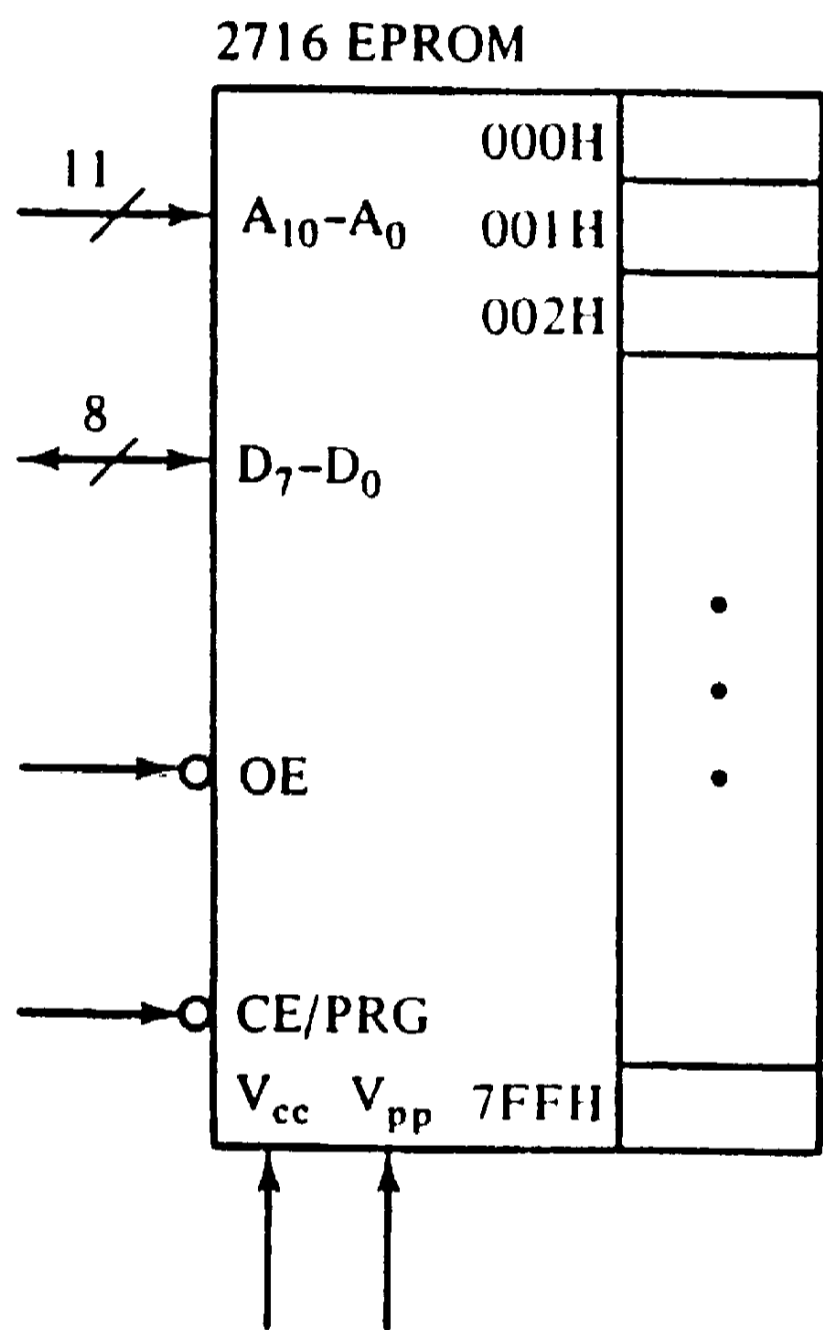
Figure 6.31 Basic operations for a dynamic RAM.



Operation	CE
Disable memory	0
Read	1

Where 0: false
1: true

Figure 6.27 A model of a read-only memory under normal operation.

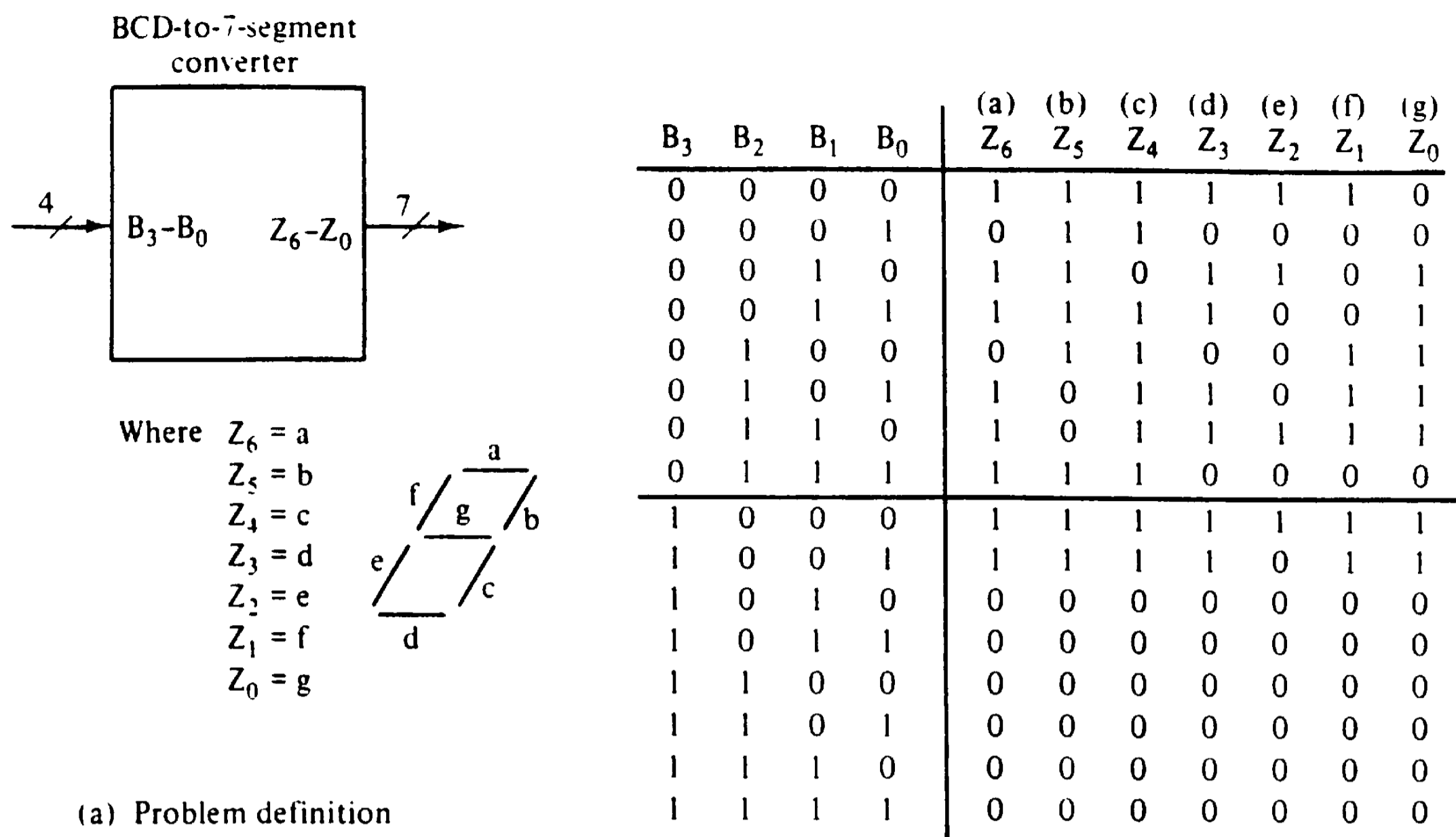


Operation	CE/PRG	OE	V_{pp}	V_{cc}	Outputs
Read	L	L	+5 V	+5 V	D_7-D_0 OUT
Standby	H	X	+5 V	+5 V	High Z
Program	Pulsed L → H	H	+25 V	+5 V	D_7-D_0 IN
Program verify	L	L	+25 V	+5 V	D_7-D_0 OUT
Program inhibit	L	H	+25 V	+5 V	High Z

(a) Block diagram of the 2716 EPROM

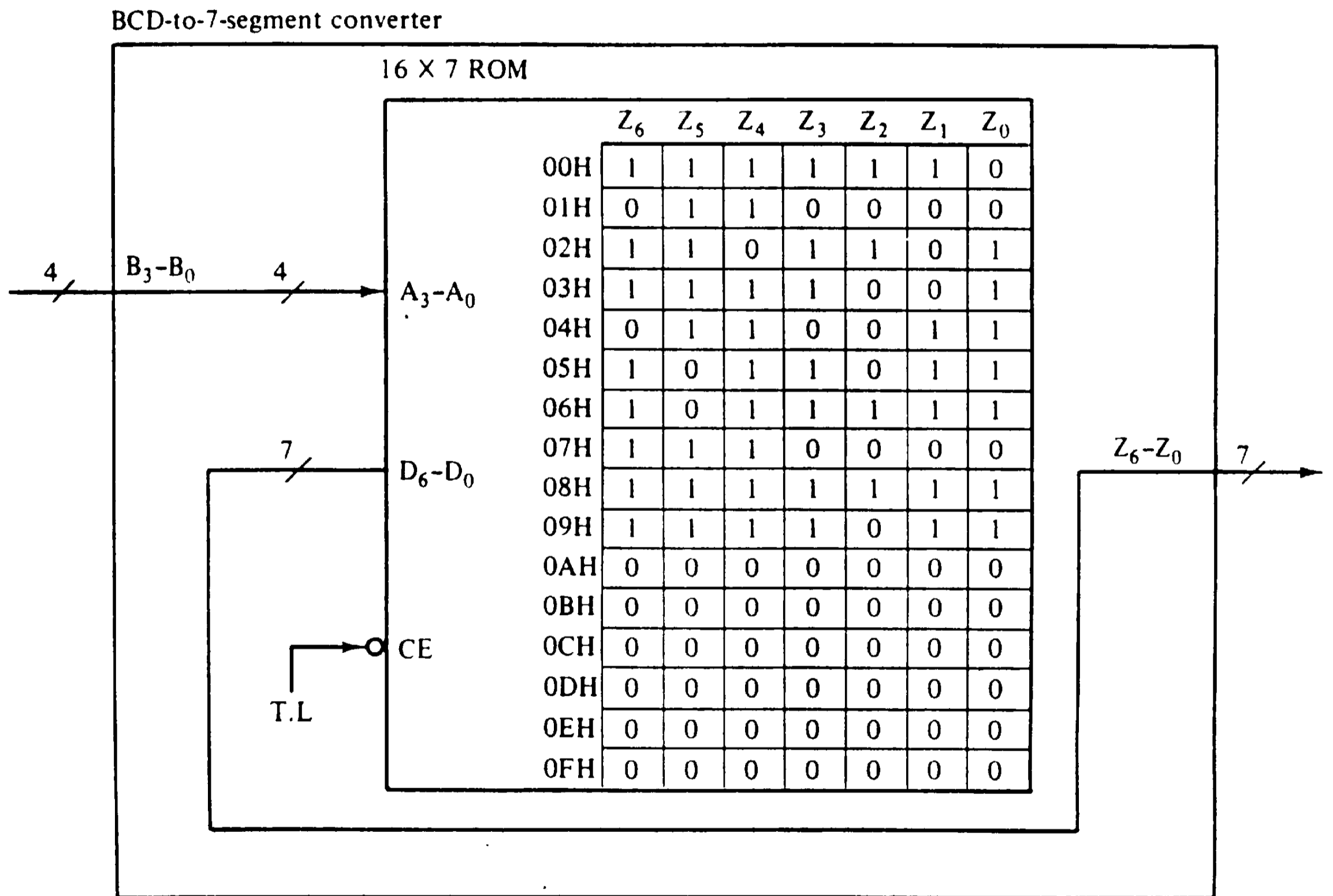
(b) Table of operations

Figure 6.29 The 2716 EPROM.



(a) Problem definition

(b) Truth table



(c) ROM realization

Figure 6.28 ROM realization of a BCD-to-7-segment converter.